

Application/Control No.	Applicant(s)/Patent under Reexamination
10/585,863	GAO ET AL.
Examiner	Art Unit
YONG D. PAK	1652

	SEARCHED					
Class	Subclass	Date	Examiner			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
435	194	4/9/2010	YP		
435	440	4/9/2010	YP		
536	23.2	4/9/2010	YP		
STIC: SEQ ID NO:2		4/9/2010	ΥP		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
STIC: SEQ ID NO:2, SEE SCORE	4/9/2010	ΥP		
EAST (all databases): inventor & text search, see search history	4/9/2010	ΥP		
PALM: inventor search	4/9/2010	ΥP		